Most Frequently Occurring Classifications of Patents Returned
From A Search of 10063787 on June 01, 2006

Original Classifications
  2   73/626

Cross-Reference Classifications
  2 706/45
  2 714/735
  2 714/736
  2 714/738
  2 714/741

Combined Classifications
  3 706/45
  2   73/626
  2 324/158.1
  2 324/73.1
  2 714/724
  2 714/726
  2 714/735
  2 714/736
  2 714/738
  2 714/741
  2 714/820

Titles of Most Frequently Occurring Classifications of Patents Returned
From A Search of 10063787 on June 01, 2006

3 706/45   (1 OR, 2 XR)
        Class   706 :   DATA PROCESSING: ARTIFICIAL INTELLIGENCE
        706/45   KNOWLEDGE PROCESSING SYSTEM

2 73/626   (2 OR, 0 XR)
        Class   073 :   MEASURING AND TESTING
        73/570   VIBRATION
        73/584   .By mechanical waves
        73/596   ..Beamed
        73/618   ...Measuring or testing system having scanning
                            means
        73/620   ....By reflected wave
        73/625   .....Having plural sonic type transmitter or
                            receiver transducers
        73/626   ......Switched

2 324/158.1   (1 OR, 1 XR)
        Class   324 :   ELECTRICITY: MEASURING AND TESTING
        324/158.1   MISCELLANEOUS

2 324/73.1   (1 OR, 1 XR)
        Class   324 :   ELECTRICITY: MEASURING AND TESTING
        324/73.1   PLURAL, AUTOMATICALLY SEQUENTIAL TESTS

2 714/724   (1 OR, 1 XR)
        Class   714 :   ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/699   PULSE OR DATA ERROR HANDLING
        714/724   .Digital logic testing

2 714/726   (1 OR, 1 XR)
        Class   714 :   ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/699   PULSE OR DATA ERROR HANDLING
        714/724   .Digital logic testing
        714/726   ..Scan path testing (e.g., level sensitive scan
                            design (LSSD))

2 714/735   (0 OR, 2 XR)
        Class   714 :   ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/699   PULSE OR DATA ERROR HANDLING
        714/724   .Digital logic testing
        714/735   ..Device response compared to input pattern

2 714/736   (0 OR, 2 XR)
        Class   714 :   ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/699   PULSE OR DATA ERROR HANDLING
        714/724   .Digital logic testing
        714/736   ..Device response compared to expected
                            fault-free response

2 714/738   (0 OR, 2 XR)
        Class   714 :   ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/699   PULSE OR DATA ERROR HANDLING
        714/724   .Digital logic testing
        714/738   ..Including test pattern generator

```
2  714/741        (0 OR, 2 XR)
        Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/699          PULSE OR DATA ERROR HANDLING
        714/724          .Digital logic testing
        714/738          ..Including test pattern generator
        714/741          ...Simulation

2  714/820        (1 OR, 1 XR)
        Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/699          PULSE OR DATA ERROR HANDLING
        714/799          .Error/fault detection technique
        714/819          ..Comparison of data
        714/820          ...Plural parallel devices of channels
```